

Notice of References Cited	Application/Control No. 10/642,790	Applicant(s)/Patent Under Reexamination MURAKAMI, TAKEHIKO	
	Examiner Randall Chin	Art Unit 1744	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2004/0049869	03-2004	Tawara et al.	015/041.1
	B	US-5,655,252	08-1997	Miyawaki et al.	15/308
	C	US-6,783,600	08-2004	Tawara et al.	134/6
	D	US-6,036,787	03-2000	Bennett et al.	134/21
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	6-297681	10-1994	Japan		
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.